INTEGRATED CIRCUITS



Product specification

1992 Jun 15

IC15 Data Handbook



HILIP

Philips Semiconductors

FEATURES

- Independent synchronous inputs and outputs
- Organized as 16 words of 5 bits
- DC to 25MHz data rate
- 3–State outputs
- Cascadable in word-width and depth direction

DESCRIPTION

This 80–bit active element First–In–First–Out (FIFO) is a monolithic Schottky–clamped transistor–transistor logic (STTL) array organized as 16–words of 5–bits each. A memory system using the 'F225 can be easily expanded in multiples of 16–words of 5–bits as shown in Figure 1. The 3–State outputs controlled by a single enable input (\overline{OE}) make bus connection and multiplexing simple. The 'F225 processes data in a parallel format at any desired clock rate from DC to 25MHz. Status of the 'F225 is provided by three outputs, Input

INPUT AND OUTPUT LOADING AND FAN OUT TABLE

Ready (IR), Unload Clock Output (UNCPOUT) and Output Ready (OR). The data outputs are non-inverting with respect to the data inputs and are disabled when the \overline{OE} input is High. When \overline{OE} is Low, the data outputs are enabled to function as totem-pole outputs.

ТҮРЕ	TYPICAL f _{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F225	25MHz	65mA

ORDERING INFORMATION

	ORDER CODE	
DESCRIPTION	$\label{eq:commercial RANGE} \begin{array}{l} \text{COMMERCIAL RANGE} \\ \text{V}_{\text{CC}} = 5\text{V} \pm 10\%, \\ \text{T}_{\text{amb}} = 0^{\circ}\text{C} \text{ to } + 70^{\circ}\text{C} \end{array}$	PKG DWG #
20-pin plastic DIP	N74F225N	SOT146-1
20-pin plastic SOL	N74F225D	SOT163-1

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
CPA, CPB	Load clock A and load clock B inputs	1.0/0.033	20μΑ/20μΑ
D0 – D4	Data inputs	1.0/0.033	20μΑ/20μΑ
ŌĒ	Output enable input (active-Low)	1.0/0.033	20μΑ/20μΑ
UNCPIN	Unload clock input	1.0/0.033	20μΑ/20μΑ
MR	Master reset input (active-Low)	1.0/0.033	20μΑ/20μΑ
IR	Input ready output	50/33	1.0mA/20mA
UNCPOUT	Unload clock output (active–Low)	50/33	1.0mA/20mA
Q0 – Q4	Data outputs	150/40	3.0mA/24mA
OR	Output ready output	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

RESET MODE

A High–to–Low transition on the Master Reset (\overline{MR}) input invalidates all data stored in the FIFO by clearing the control logic and setting OR Low. This High–to–Low transition on the \overline{MR} input does not effect the data outputs but since OR is driven Low, it signifies invalid data on the outputs.

WRITE MODE

Data may be written into the array on the Low-to-High transition of either load clock (CPA or CPB) input. When writing data into the FIFO, one of the load clock inputs must be held High while the other strobes data into the FIFO. This arrangement allows either load clock to function as an inhibit for the other. Input Ready (IR) monitors the status of the last word location and signifies when the FIFO is full. This output is High whenever the FIFO is available to accept new data. The unload clock output (UNCPOUT) also monitors the last word location. This output generates a Low-logic-level pulse (synchronized to the internal clock pulse) when the last word location is vacant

READ MODE

The Output Ready (OR) output is High when valid data is present on the data outputs. Data in the array is shifted on the Low–to–High transition of the Unload Clock Input (UNCPIN). In order for Output Ready (OR) to go High, Unload Clock Input (UNCPIN) must also be High.

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PIN CONFIGURATION



LOGIC SYMBOL



IEC/IEEE SYMBOL



LOGIC DIAGRAM



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ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMET	ſER	RATING	UNIT
V _{CC}	Supply voltage		-0.5 to +7.0	V
V _{IN}	Input voltage		-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA	
V _{OUT}	Voltage applied to output in High output state		–0.5 to V_{CC}	V
I _{OUT}	Current applied to output in Low output state	IR, OR, UNCPOUT	40	mA
	Current applied to output in Low output state	Data outputs	48	mA
T _{amb}	Operating free air temperature range		0 to +70	°C
T _{stg}	Storage temperature range		-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PAR	AMETER		LIMITS		UNIT
			MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5.0	5.5	V	
V _{IN}	High-level input voltage		2.0			V
V _{IL}	Low-level input voltage	Low-level input voltage				V
۱ _{lk}	Input clamp current			-18	mA	
I _{ОН}	High-level output current	IR, OR, UNCPOUT			-1	mA
		Data outputs			-3	mA
I _{OL}	Low-level output current	IR, OR, UNCPOUT			20	mA
		Data outputs			24	mA
T _{amb}	Operating free air temperature ran	ge	0		+70	°C

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DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETE	R	TEST CONDITION	ONS ¹	LIMITS			UNIT
					MIN	TYP ²	MAX	1
		IR, OR,	$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}	2.5			V
V _{OH}	High-level output voltage	UNCPOUT	$V_{IH} = MIN, I_{OH} = MAX$	±5%V _{CC}	2.7			V
		Data	$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}	2.4			V
		outputs	$V_{IH} = MIN, I_{OH} = MAX$	±5%V _{CC}	2.7			V
V _{OL}	Low-level output voltage		$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}		0.35	0.50	V
			$V_{IH} = MIN, I_{OL} = MAX$	±5%V _{CC}		0.35	0.50	V
V _{IK}	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$			-0.73	-1.2	V
I _I	Input current at maximum in	nput voltage	$V_{CC} = MAX, V_I = 7.0V$	$V_{CC} = MAX, V_I = 7.0V$			100	μΑ
I _{IH}	High–level input current		$V_{CC} = MAX, V_I = 2.7V$	$V_{CC} = MAX, V_1 = 2.7V$			20	μΑ
١ _{IL}	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$	$V_{CC} = MAX, V_I = 0.5V$			-20	μΑ
I _{OZH}	Offset–output current, High–level voltage applied		$V_{CC} = MAX, V_I = 2.7V$				50	μΑ
I _{OZL}	Offset–output current, Low–level voltage applied		$V_{CC} = MAX, V_I = 0.5V$				-50	μΑ
I _{OS}	Short-circuit output current	3	V _{CC} = MAX	V _{CC} = MAX			-150	mA
I _{CC}	Supply current (total)		V _{CC} = MAX	$V_{CC} = MAX$		65	95	mA

NOTES:

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
Not more than one output should be shorted at a time. For testing I_{OS}, the use of High-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

					LIM	ITS		
SYMBOL	PARAMETER	TEST	v	_{mb} = +25 _{CC} = +5.0	V	T _{amb} = 0°(V _{CC} = +5.	UNIT	
		CONDITION		0pF, R _L =		/	$R_L = 500\Omega$	4
f _{MAX}	Maximum clock frequency, Cascade mode	Waveform 2 and 3	MIN 25	ITP	MAX	MIN 25	MAX	MHz
t _{PLH} t _{PHL}	Propagation delay UNCPIN to Qn	Waveform 2	10.0 9.5	13.0 12.0	19.5 16.0	9.0 8.5	22.0 19.0	ns
t _{PLH} t _{PHL}	Propagation delay UNCPIN to OR	Waveform 2	16.0 6.0	20.0 8.5	25.0 11.0	14.0 5.0	29.0 12.0	ns
t _{SK}	Output skew Qn to OR ↑	Waveform 4	2.0		12.0	0.0	15.0	ns
t _{PLH}	Propagation delay UNCPIN to IR	Waveform 2	50	60	70	50	85	ns
t _{PLH}	Propagation delay CPA or CPB to OR	Waveform 4	55	65	75	50	90	ns
t _{PLH} t _{PHL}	Propagation delay CPA or CPB to UNCPOUT	Waveform 4	20.0 8.5	23.0 11.5	27.0 15.0	17.0 7.5	29.0 16.0	ns
t _w (L)	Pulse width, Low UNCPOUT	Waveform 4		12.0				ns
t _{PHL}	Propagation delay CPA or CPB to IR	Waveform 3	11.0	13.5	17.0	9.0	19.0	ns
t _{PHL}	Propagation delay MR to OR	Waveform 3	5.5	8.5	11.5	5.0	13.0	ns
t _{PHL}	Propagation delay MR to IR	Waveform 3	2.0	4.0	7.0	1.5	7.5	ns
t _{PZH} t _{PZL}	Output enable time to High or Low level	Waveform 5 Waveform 6	1.5 2.5	3.5 4.5	6.5 7.5	1.0 2.0	7.0 9.0	ns
t _{PHZ} t _{PLZ}	Output disable time from High or Low level	Waveform 5 Waveform 6	1.5 2.0	3.5 4.0	7.0 7.0	1.0 1.5	7.5 7.5	ns

AC SETUP REQUIREMENTS

					LIM	ITS		
SYMBOL	PARAMETER	TEST CONDITION	v,	_{mb} = +25 _{CC} = +5.0 0pF, R _L =	V	$T_{amb} = 0^{\circ}C$ $V_{CC} = +5.$ $C_{L} = 50pF,$	0V \pm 10%	UNIT
			MIN	TYP	MAX	MIN	MAX	
t _s (H) t _s (L)	Setup time, High or Low Dn to CPA or CPB	Waveform 1	0.0 0.0			0.0 0.0		ns
t _h (H) t _h (L)	Hold time, High or Low Dn to CPA or CPB	Waveform 1	14.0 12.5			16.5 14.0		ns
t _{rec}	Recovery time MR to CPA or CPB	Waveform 1	0.0			0.0		ns
t _w (H) t _w (L)	CPA or CPB pulse width, High or Low	Waveform 1	6.5 3.0			8.5 3.5		ns
t _w (L)	UNCPIN pulse width, High or Low	Waveform 2	24.0 3.5			28.0 4.0		ns
t _w (L)	MR pulse width, Low	Waveform 1	3.5			4.5		ns

TYPICAL TIMING DIAGRAM



NOTE: Shaded areas Indicates irrelevant input conditions.

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AC WAVEFORMS







Waveform 2. UNCPIN to Output Delays



Waveform 3. CPA or CPB to IR Delay and MR to IR and OR Delay

NOTES:

1. For all waveforms, $V_M = 1.5V$.

2. The shaded areas indicate when the input is permitted to change for predictable output performance.



Waveform 4. CPA or CPB to UNCPOUT and OR Delay, UNCPOUT Pulse Width and Qn to OR Skew



Waveform 5. 3-State Output Enable Time to High Level and Output Disable Time from High Level



Waveform 6. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

APPLICATION



Figure 1. Expanding the 74F225 FIFO (48 words of 10 bits)

TEST CIRCUIT AND WAVEFORM



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DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	c	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	M _E	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.0
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	RENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE
SOT146-1			SC603		-92-11-17- 95-05-24

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SOT146-1

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Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	RENCES				
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT163-1	075E04	MS-013AC				-95-01-24 97-05-22	

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NOTES

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Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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